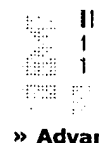


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Example: optical <and> (fiber <or> fibre) <in> ti

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```
(stereo <near/5> imag*)
<paragraph> (((estimat* or
project* or predict* or
interpolat*) <near/4> (imag*
```

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Note: This function returns plural and suffixed forms of the keyword(s).

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And

stereo In: All Fields

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In: All Fields

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